



PTO/SB/08a/b (08-03)
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INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		Application Number	10/750,838-Conf. #2502
		Filing Date	January 5, 2004
		First Named Inventor	Shuichi Takeuchi
		Art Unit	NTA 2881
		Examiner Name	Not Yet Assigned Fernandez
Sheet 1 of 1	Attorney Docket Number	H6808.0032/P032	

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
KF	AA**	6,538,249	03-25-2003	Takane et al.	
KF	AB**	6,353,222	03-05-2002	Noam Dotan	

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No. ¹	Foreign Patent Document Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
KF	BA	JP 2001-84944	03-30-2001			
	BB	JP 2001-118537	04-27-2001			
	BC	JP 2001-344599	12-14-2001			
	BD	JP 2002-75263	03-15-2002			
KF	BE	JP 2002-184336	06-28-2002			

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
KF	CA	A. Muto et al., "Attempts to Improve SEM Image Quality by Special Imaging Feature." Proceedings of the Fifty-Eighth Annual Meeting of the Japanese Society of Electron Microscopy, May 14-16, 2002, pp.246. English Translation.	
	CB	M. Sato et al., "Depth of Field at High Magnifications of Scanning Electron Microscopes." J. Vac. Sci. Technol. B 18(6), Nov/Dec. 2000, pp.3047-3051.	
	CC	T. Kogashiwa et al., "Automatic Adjustment Function of Optical Axis, and automatic Expansion Function of Focal Depth." SCAN TECH 2002, Preliminary Report, September 2002, pp. 2-6. English Translation.	
KF	CD	Norio Baba, "Three-dimensional Automatic Measurement by the Stereoscopic Observation Method." SCAN TECH 2000, Preliminary Report, September 2000, pp. 28-32. English Translation.	

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